Emil Agocs

List of Publications by Year
in descending order

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24 papers	189 citations	1039406 9 h-index	1058022 14 g-index
24 all docs	24 docs citations	24 times ranked	280 citing authors

#	Article	IF	Citations
1	Approaches to calculate the dielectric function of ZnO around the band gap. Thin Solid Films, 2014, 571, 684-688.	0.8	24
2	Plasmon-enhanced two-channel in situ Kretschmann ellipsometry of protein adsorption, cellular adhesion and polyelectrolyte deposition on titania nanostructures. Optics Express, 2016, 24, 4812.	1.7	16
3	Porosity and thickness characterization of porous Si and oxidized porous Si layers â€“ An ultravioletâ€“visibleâ€“mid infrared ellipsometry study. Microporous and Mesoporous Materials, 2016, 227, 112-120.	2.2	16
4	Spectroscopic ellipsometry of columnar porous Si thin films and Si nanowires. Applied Surface Science, 2017, 421, 397-404.	3.1	16
5	Highly transparent ITO thin films on photosensitive glass: solâ€“gel synthesis, structure, morphology and optical properties. Applied Physics A: Materials Science and Processing, 2012, 107, 385-392.	1.1	15
6	Bilayered (silicaâ€“chitosan) coatings for studying dye release in aqueous media: The role of chitosan properties. Carbohydrate Polymers, 2016, 136, 137-145.	5.1	15
7	Doping silica beyond limits with laser plasma for active photonic materials. Optical Materials Express, 2015, 5, 2849.	1.6	14
8	Investigation of thin polymer layers for biosensor applications. Applied Surface Science, 2013, 281, 66-72.	3.1	13
9	Optical characterization of nanocrystals in silicon rich oxide superlattices and porous silicon. Thin Solid Films, 2011, 519, 3002-3005.	0.8	12
10	Comparative measurements on atomic layer deposited Al2O3 thin films using ex situ table top and mapping ellipsometry, as well as X-ray and VUV reflectometry. Thin Solid Films, 2013, 541, 131-135.	0.8	9
11	Resolving lateral and vertical structures by ellipsometry using wavelength range scan. Thin Solid Films, 2014, 571, 579-583.	0.8	8
12	Grating coupled optical waveguide interferometry combined with in situ spectroscopic ellipsometry to monitor surface processes in aqueous solutions. Applied Surface Science, 2017, 421, 289-294.	3.1	7
13	Spectroscopic ellipsometry studies on the optical constants of Bi4Ti3O12:xNa thin films grown by metal-organic chemical vapor deposition. Thin Solid Films, 2011, 519, 3782-3788.	0.8	6
14	Model dielectric function analysis of the critical point features of silicon nanocrystal films in a broad parameter range. Thin Solid Films, 2013, 541, 83-86.	0.8	4
15	Characterization of damage structure in ion implanted SiC using high photon energy synchrotron ellipsometry. Thin Solid Films, 2011, 519, 2791-2794.	0.8	3
16	In Situ Characterization of Biomaterials at Solidâ€Liquid Interfaces Using Ellipsometry in the UVâ€Visibleâ€NIR Wavelength Range. Physica Status Solidi (A) Applications and Materials Science, 2019, 216, 1800762.	0.8	3
17	Concordant element of the oxidation kineticsâ€”Interpretation of ellipsometric measurements on Zr. Applied Surface Science, 2022, 573, 151543.	3.1	3
18	Optical constants of MOCVD-grown Aurivillius phases in the Bi4Ti3O12â€“Na0.5Bi0.5TiO3 system measured by spectroscopic ellipsometry. Applied Physics A: Materials Science and Processing, 2011, 105, 81-88.	1.1	2

#	Article	IF	Citations
19	Composite polymeric-inorganic waveguide fabricated by injection molding for biosensing applications. , 2014, , .		1
20	Characterization of in-depth cavity distribution after thermal annealing of helium-implanted silicon and gallium nitride. Thin Solid Films, 2014, 571, 567-572.	0.8	1
21	Optical Properties of Oxidized, Hydrogenated, and Native Zirconium Surfaces for Wavelengths from 0.3 to 25â€‰Âµm â^' A Study by Ex Situ and In Situ Spectroscopic Ellipsometry. Physica Status Solidi (A) Applications and Materials Science, 2019, 216, 1800676.	0.8	1
22	Spectroellipsometric and ion beam analytical studies on a glazed ceramic object with metallic lustre decoration. Thin Solid Films, 2014, 571, 715-719.	0.8	0
23	Whether Ge-Rich ZrO2 and Ge-Rich HfO2 Materials Have Similar Reaction on Annealing Treatment?. ECS Transactions, 2020, 97, 49-60.	0.3	0
24	Whether Ge-Rich ZrO2 and Ge-Rich HfO2 Materials Have Similar Reaction on Annealing Treatment?. ECS Meeting Abstracts, 2020, MA2020-01, 1027-1027.	0.0	0